

SN54LS353, SN74LS353

DUAL 4-LINE TO 1-LINE DATA SELECTORS/MULTIPLEXERS

WITH 3-STATE OUTPUTS

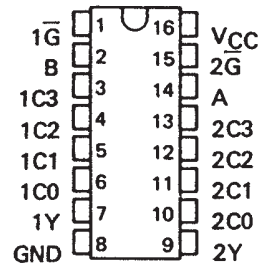
SDLS163 – OCTOBER 1976 – REVISED MARCH 1988

- Inverting Versions of SN54LS253, SN74LS253
- Schottky-Diode-Clamped Transistors
- Permits Multiplexing from N lines to 1 line
- Performs Parallel-to-Serial Conversion
- Typical Average Propagation Delay Times:
 - Data Input to Output . . . 12 ns
 - Control Input to Output . . . 16 ns
 - Select Input to Output . . . 21 ns
- Fully Compatible with most TTL Circuits
- Low Power Dissipation . . . 35 mW Typical (Enabled)
- Inverted Data

SN54LS353 . . . J OR W PACKAGE

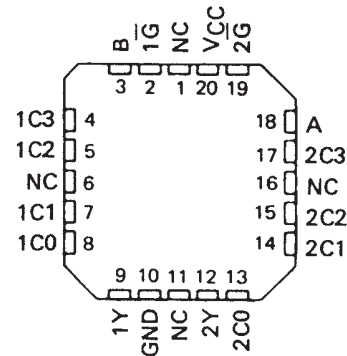
SN74LS353 . . . D OR N PACKAGE

(TOP VIEW)



SN54LS353 . . . FK PACKAGE

(TOP VIEW)



NC – No internal connection

description

Each of these Schottky-clamped data selectors/multiplexers contains inverters and drivers to supply fully complementary, on-chip, binary decoding data selection to the AND-OR-invert gates. Separate output control inputs are provided for each of the two four-line sections.

The three-state outputs can interface with and drive data lines of bus-organized systems. With all but one of the common outputs disabled (at a high-impedance state) the low-impedance of the single enabled output will drive the bus line to a high or low logic level.

FUNCTION TABLE

SELECT INPUTS		DATA INPUTS				OUTPUT CONTROL	OUTPUT
B	A	C0	C1	C2	C3	$\bar{G}$	Y
X	X	X	X	X	X	H	Z
L	L	L	X	X	X	L	H
L	L	H	X	X	X	L	L
L	H	X	L	X	X	L	H
L	H	X	H	X	X	L	L
H	L	X	X	L	X	L	H
H	L	X	X	H	X	L	L
H	H	X	X	X	L	L	H
H	H	X	X	X	H	L	L

Select inputs A and B are common to both sections.

H = high level, L = low level, X = irrelevant, Z = high impedance (off)

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage	7 V
Off-state output voltage	5.5 V
Operating free-air temperature range: SN54LS353	–55°C to 125°C
SN74LS353	0°C to 70°C
Storage temperature range	–65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



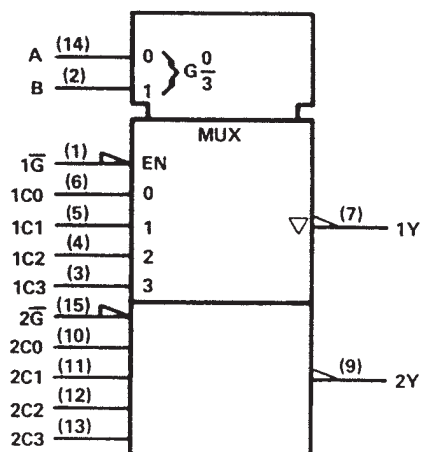
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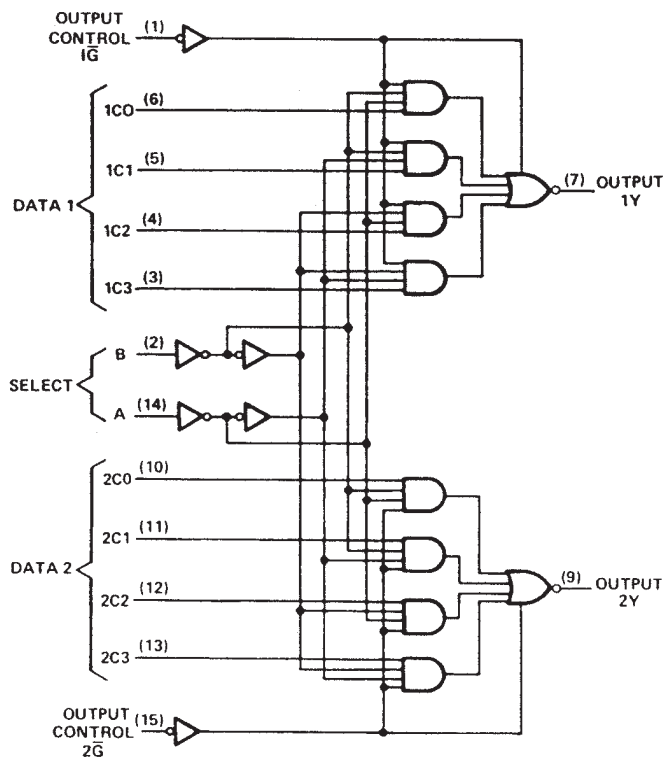
logic symbol†



†This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

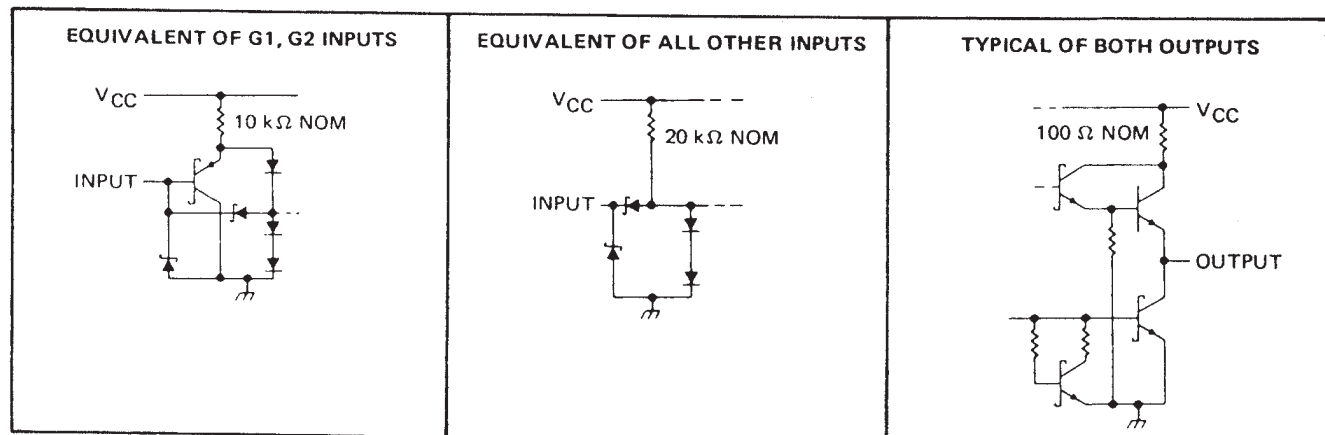
Pin numbers shown are for D, J, N, and W packages.

logic diagram (positive logic)



Pin numbers shown are for D, J, N, and W packages.

schematic of inputs and outputs



SN54LS353, SN74LS353

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recommended operating conditions

	SN54LS353			SN74LS353			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.7			0.8	V
I _{OH} High-level output current			– 1			– 2.6	mA
I _{OL} Low-level output current			4			8	mA
T _A Operating free-air temperature	– 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS †		SN54LS353		SN74LS353		UNIT
				MIN	TYP‡	MAX	MIN	
V _{IK}		V _{CC} = MIN, I _I = – 18 mA		– 1.5		– 1.5		V
V _{OH}		V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = MAX, I _{OH} = MAX		2.4	3.4	2.4	3.1	V
V _{OL}		V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = MAX	I _{OL} = 4 mA	0.25	0.4	0.25	0.4	V
			I _{OL} = 8 mA			0.35	0.5	
I _{OZ}		V _{CC} = MAX, V _{IH} = 2 V	V _O = 2.7 V	20		20		μA
			V _O = 0.4 V	– 20		– 20		
I _I		V _{CC} = MAX, V _I = 7 V		0.1		0.1		mA
I _{IH}		V _{CC} = MAX, V _I = 2.7 V		20		20		μA
I _{IL}	G1, G1	V _{CC} = MAX, V _I = 0.4 V		– 0.2		– 0.2		mA
	All other			– 0.4		– 0.4		
I _{OS} §		V _{CC} = MAX		– 30	– 130	– 30	– 130	mA
I _{CC}		V _{CC} = MAX, See Note 2	Condition A	7	12	7	12	mA
			Condition B	8.5	14	8.5	14	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

NOTE 2: I_{CC} is measured with the outputs open under the following conditions:

- A. All inputs grounded.
- B. Output control at 4.5 V, all inputs grounded.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER¶	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Data	Y	C _L = 15 pF, R _L = 2 kΩ, See Note 3	11	25	ns	
t _{PHL}				13	20		
t _{PLH}	Select	Y		20	45	ns	
t _{PHL}				21	32		
t _{PZH}	Output Control	Y		11	23	ns	
t _{PZL}				15	23		
t _{PHZ}	Output Control	Y	C _L = 5 pF, R _L = 2 kΩ, See Note 3	27	41	ns	
t _{PLZ}			12	27			

¶ t_{PLH} = Propagation delay time, low-to-high-level output

t_{PHL} = Propagation delay time, high-to-low-level output

t_{PZH} = Output enable time to high level

t_{PZL} = Output enable time to low level

t_{PHZ} = Output disable time from high level

t_{PLZ} = Output disable time from low level

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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